

**Retraction: “Broadband and omnidirectional antireflection from conductive indium-tin-oxide nanocolumns prepared by glancing-angle deposition with nitrogen” [Appl. Phys. Lett. 94, 051114 (2009)]**

C. H. Chang, Peichen Yu, and C. S. Yang

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The authors wish to retract this paper<sup>1</sup> due to overlap of content with their previously published paper in *Advanced Materials*,<sup>2</sup> including duplicated SEM images and measurement data. The regrettable mistake was a result of mishandling of experimental data with high resemblance. For that, the authors apologize to the readers and the editorial office of *Applied Physics Letters* for any confusion caused.

<sup>1</sup>C. H. Chang, P. Yu, and C. S. Yang, *Appl. Phys. Lett.* **94**, 051114 (2009).

<sup>2</sup>P. Yu, C.-H. Chang, C.-H. Chiu, C.-S. Yang, J.-C. Yu, H.-C. Kuo, S.-H. Hsu, and Y.-C. Chang, *Adv. Mater.* **21**, 1618 (2009).